International TOR Rectifier

Features

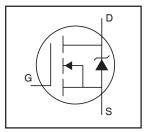
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free

Description

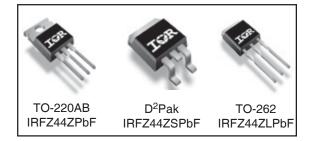
This HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.

IRFZ44ZPbF IRFZ44ZSPbF IRFZ44ZLPbF

HEXFET® Power MOSFET



$$V_{DSS} = 55V$$
 $R_{DS(on)} = 13.9 m\Omega$
 $I_D = 51A$



Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	51	Α
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (See Fig. 9)	36	
I _{DM}	Pulsed Drain Current ①	200	
P _D @T _C = 25°C	Maximum Power Dissipation	80	W
	Linear Derating Factor	0.53	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	86	mJ
E _{AS} (tested)	Single Pulse Avalanche Energy Tested Value ⑦	105	
I _{AR}	Avalanche Current ①	See Fig.12a,12b,15,16	Α
E _{AR}	Repetitive Avalanche Energy ®		mJ
TJ	Operating Junction and	-55 to + 175	°C
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.87	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		
$R_{\theta JA}$	Junction-to-Ambient		62	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount, steady state)®		40	

Static @ $T_J = 25^{\circ}C$ (unless otherwise specified)

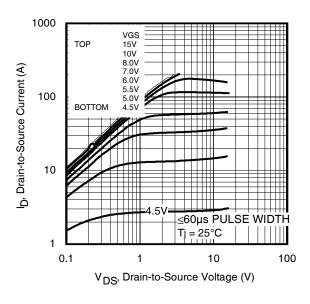
Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
Breakdown Voltage Temp. Coefficient		0.054		V/°C	Reference to 25°C, I _D = 1mA
Static Drain-to-Source On-Resistance		11.1	13.9	mΩ	V _{GS} = 10V, I _D = 31A ④
Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Forward Transconductance	22			S	$V_{DS} = 25V, I_D = 31A$
Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 55V, V_{GS} = 0V$
			250	1	$V_{DS} = 55V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
Gate-to-Source Forward Leakage			200	nA	V _{GS} = 20V
Gate-to-Source Reverse Leakage			-200	1	V _{GS} = -20V
Total Gate Charge		29	43	nC	I _D = 31A
Gate-to-Source Charge		7.2	11	1	$V_{DS} = 44V$
Gate-to-Drain ("Miller") Charge		12	18	1	V _{GS} = 10V ④
Turn-On Delay Time		14		ns	$V_{DD} = 28V$
Rise Time		68			$I_D = 31A$
Turn-Off Delay Time		33		1	$R_G = 15\Omega$
Fall Time		41		1	V _{GS} = 10V ④
Internal Drain Inductance		4.5		nH	Between lead, p
					6mm (0.25in.)
Internal Source Inductance		7.5			from package
					and center of die contact
Input Capacitance		1420		pF	V _{GS} = 0V
Output Capacitance		240			$V_{DS} = 25V$
Reverse Transfer Capacitance		130		1	f = 1.0MHz, See Fig. 5
Output Capacitance		830		Í	$V_{GS} = 0V$, $V_{DS} = 1.0V$, $f = 1.0MHz$
Output Capacitance		190	_	1	$V_{GS} = 0V$, $V_{DS} = 44V$, $f = 1.0MHz$
Effective Output Capacitance		300	_	1	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 44V$
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Source Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Input Capacitance Output Capacitance Output Capacitance Output Capacitance Output Capacitance Output Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Source Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Input Capacitance Output Capacitance	Drain-to-Source Breakdown Voltage 55 Breakdown Voltage Temp. Coefficient — 0.054 Static Drain-to-Source On-Resistance — 11.1 Gate Threshold Voltage 2.0 Forward Transconductance 22 Drain-to-Source Leakage Current — — Gate-to-Source Forward Leakage — — Gate-to-Source Reverse Leakage — — Total Gate Charge — 29 Gate-to-Source Charge — 7.2 Gate-to-Drain ("Miller") Charge — 12 Turn-On Delay Time — 14 Rise Time — 68 Turn-Off Delay Time — 33 Fall Time — 41 Internal Drain Inductance — 4.5 Internal Source Inductance — 7.5 Input Capacitance — 1420 Output Capacitance — 240 Reverse Transfer Capacitance — 330 Output Capacitance — 830 Output Capacitance — 190	Drain-to-Source Breakdown Voltage 55 — Breakdown Voltage Temp. Coefficient — 0.054 — Static Drain-to-Source On-Resistance — 11.1 13.9 Gate Threshold Voltage 2.0 — 4.0 Forward Transconductance 22 — — Drain-to-Source Leakage Current — 20 — — 250 Gate-to-Source Forward Leakage — — 200 — — 200 Gate-to-Source Reverse Leakage — — 200 — — 200 — — 200 Gate-to-Source Reverse Leakage — — — 200 — — 200 — — 200 — — 200 — — 200 — — 200 — — 200 — — 200 — — 200 — — 200 — — 201 — — — 200 — <t< td=""><td>Drain-to-Source Breakdown Voltage 55 — V Breakdown Voltage Temp. Coefficient — 0.054 — V/°C Static Drain-to-Source On-Resistance — 11.1 13.9 mΩ Gate Threshold Voltage 2.0 — 4.0 V Forward Transconductance 22 — — S Drain-to-Source Leakage Current — — 20 µA — — 250 — 4.0 V Gate-to-Source Leakage Current — — 20 µA Gate-to-Source Forward Leakage — — 200 nA Gate-to-Source Reverse Leakage — — 200 nA Gate-to-Source Charge — 29 43 nC Gate-to-Source Charge — 7.2 11 Gate-to-Source Charge — 12 18 Turn-On Delay Time — 14 — ns ns Rise Time — 68 —</td></t<>	Drain-to-Source Breakdown Voltage 55 — V Breakdown Voltage Temp. Coefficient — 0.054 — V/°C Static Drain-to-Source On-Resistance — 11.1 13.9 mΩ Gate Threshold Voltage 2.0 — 4.0 V Forward Transconductance 22 — — S Drain-to-Source Leakage Current — — 20 µA — — 250 — 4.0 V Gate-to-Source Leakage Current — — 20 µA Gate-to-Source Forward Leakage — — 200 nA Gate-to-Source Reverse Leakage — — 200 nA Gate-to-Source Charge — 29 43 nC Gate-to-Source Charge — 7.2 11 Gate-to-Source Charge — 12 18 Turn-On Delay Time — 14 — ns ns Rise Time — 68 —

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			51		MOSFET symbol
	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current			200		integral reverse
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.2	V	$T_J = 25^{\circ}C$, $I_S = 31A$, $V_{GS} = 0V$ ④
t _{rr}	Reverse Recovery Time		23	35	ns	$T_J = 25^{\circ}C$, $I_F = 31A$, $V_{DD} = 28V$
Q_{rr}	Reverse Recovery Charge		17	26	nC	di/dt = 100A/µs ⊕
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by T_{Jmax} , starting $T_J = 25^{\circ}C$, L = 0.18mH, $R_G = 25\Omega$, $I_{AS} = 31A$, $V_{GS} = 10V$. Part not recommended for use above this value.
- $\label{eq:loss_def} \begin{tabular}{ll} $I_{SD} \leq 31A, \; di/dt \leq 840A/\mu s, \; V_{DD} \leq V_{(BR)DSS}, \\ $T_J \leq 175^{\circ}C. \end{tabular}$
- ④ Pulse width \leq 1.0ms; duty cycle \leq 2%.
- © Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- This value determined from sample failure population. 100% tested to this value in production.
- This is applied to D²Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- \mathfrak{P}_{θ} is rated at T_J of approximately 90°C.



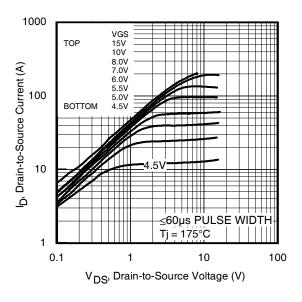
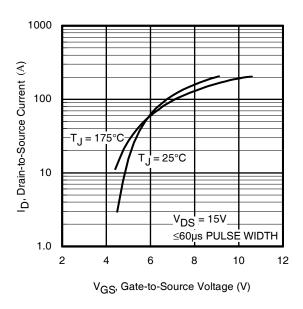
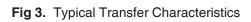


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics





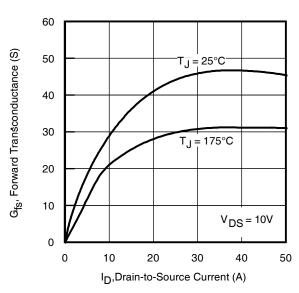
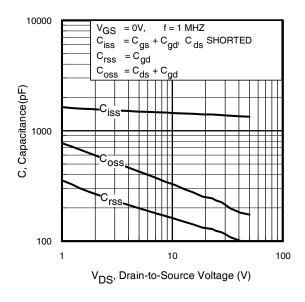


Fig 4. Typical Forward Transconductance vs. Drain Current



12.0 I_D= 31A V_{DS}= 44V 10.0 V_{GS}, Gate-to-Source Voltage (V) V_{DS}= 28V V_{DS}= 11V 8.0 6.0 4.0 2.0 0.0 10 0 15 25 30 Q_G Total Gate Charge (nC)

Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

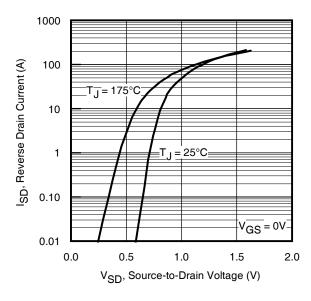


Fig 7. Typical Source-Drain Diode Forward Voltage

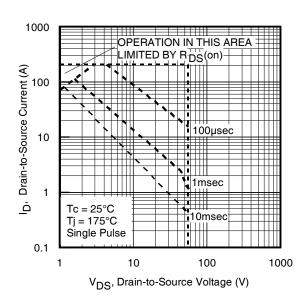
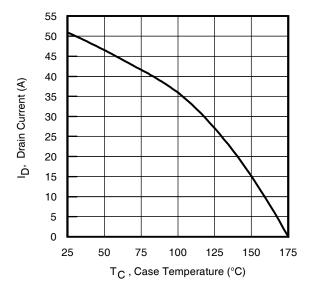


Fig 8. Maximum Safe Operating Area



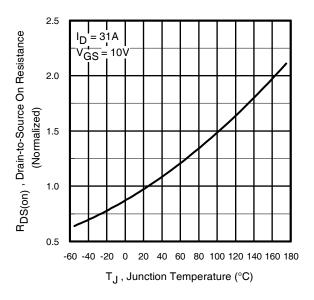


Fig 9. Maximum Drain Current vs. Case Temperature

Fig 10. Normalized On-Resistance vs. Temperature

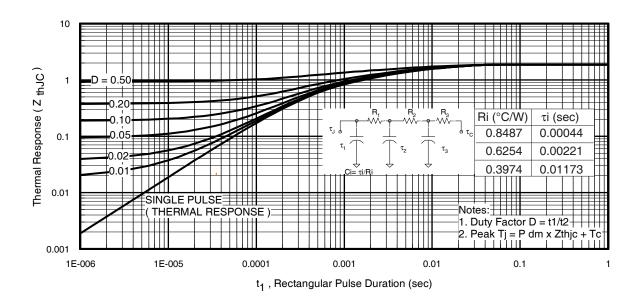


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

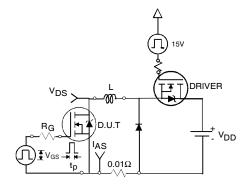


Fig 12a. Unclamped Inductive Test Circuit

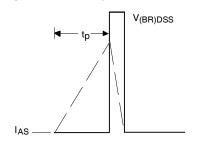


Fig 12b. Unclamped Inductive Waveforms

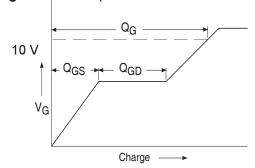


Fig 13a. Basic Gate Charge Waveform

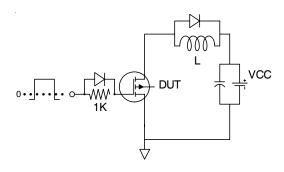


Fig 13b. Gate Charge Test Circuit

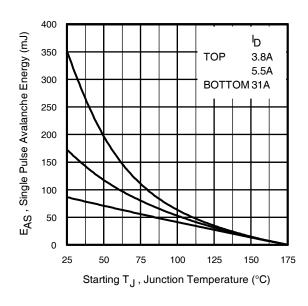


Fig 12c. Maximum Avalanche Energy vs. Drain Current

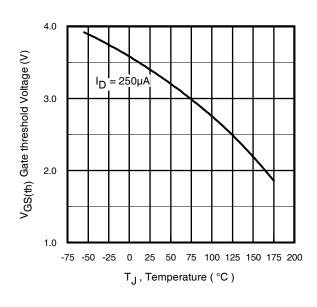


Fig 14. Threshold Voltage vs. Temperature

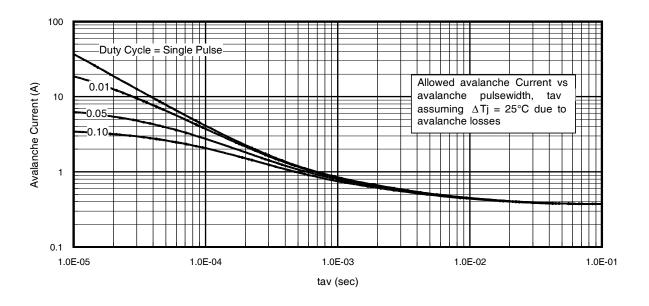


Fig 15. Typical Avalanche Current vs. Pulsewidth

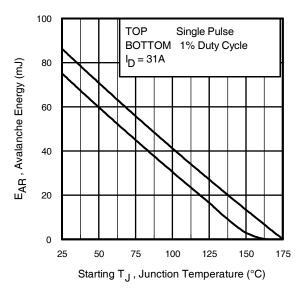


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

- Avalanche failures assumption:
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. $P_{D (ave)}$ = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16). t_{av} = Average time in avalanche.
 - D = Duty cycle in avalanche = $t_{av} \cdot f$

 $Z_{th,IC}(D, t_{av})$ = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D\;(ave)} &= 1/2\;(\;1.3\text{-BV-I}_{av}) = \triangle T/\;Z_{thJC}\\ I_{av} &= 2\triangle T/\;[1.3\text{-BV-Z}_{th}]\\ E_{AS\;(AR)} &= P_{D\;(ave)} \cdot t_{av} \end{split}$$

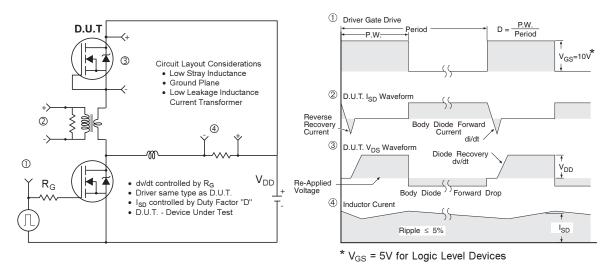


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

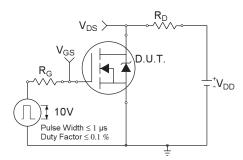


Fig 18a. Switching Time Test Circuit

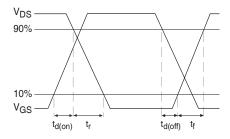
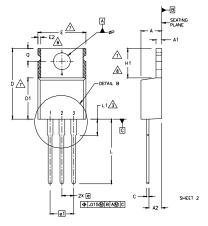
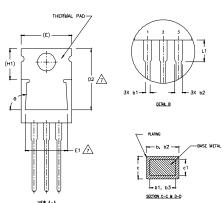


Fig 18b. Switching Time Waveforms

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)





- SI DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
 DIMENSIONIS ARE SHOWN IN INCHES [MILLIMETERS].
 LEAD DIMENSION AND FINISH UNCONTROLLED IN L.1.
 DIMENSION D. & E DO NOT INCLUDE MOLD FLASH MOLD FLASH
 SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE
 MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
 DIMENSION D. & C.1 APPLY TO BASE METAL ONLY.
 CONTROLLING DIMENSION: INCHES.
 THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
 DIMENSION E. X.1 HI DEFENE A TONE WHERE STAMPING

- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.

	DIMENSIONS				
SYMBOL	MILLIM	ETERS	INC		
	MIN.	MAX.	MIN.	MAX.	NOTES
Α	3.56	4.82	.140	.190	
A1	0.51	1,40	.020	.055	
A2	2.04	2.92	.080	.115	
b	0.38	1,01	.015	.040	
ь1	0.38	0.96	.015	.038	5
b2	1,15	1,77	.045	.070	
b3	1,15	1,73	.045	.068	
С	0.36	0.61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	12.19	12.88	.480	.507	7
Ε	9.66	10.66	.380	.420	4,7
E1	8,38	8.89	,330	,350	7
e	2,54 5,	BSC	.100	.100 BSC	
e1	5.	08	,200	BSC	
H1	5.85	6.55	.230	.270	7,8
L	12,70	14,73	,500	,580	
L1	-	6,35	-	,250	3
øΡ	3,54	4,08	,139	.161	
Q	2.54	3.42	.100	.135	
ø	90,-	-93*	90.	-93	

LEAD ASSIGNMENTS

- HEXFET
- IGHTs, CoPACK
- 1.- CATE 2.- COLLECTOR 3.- EMITTER
- DIODES

TO-220AB Part Marking Information

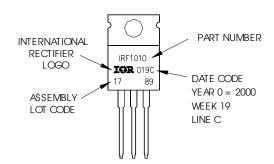
EXAMPLE: THIS IS AN IRF1010

LOT CODE 1789

ASSEMBLED ON WW 19, 2000

IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead-Free"

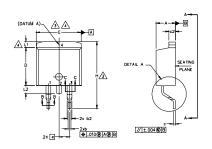


- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

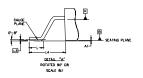
International TOR Rectifier

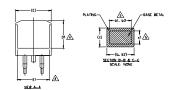
D²Pak (TO-263AB) Package Outline

Dimensions are shown in millimeters (inches)









NOTES:

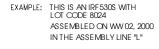
- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- A. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND C1 APPLY TO BASE METAL ONLY.
- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7, CONTROLLING DIMENSION; INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S		Ŋ			
M B O L	MILLIM	ETERS	INC	NOTES	
Ĺ	MIN,	MAX,	MIN,	MAX,	S
Α	4,06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
b	0.51	0.99	.020	.039	
b 1	0,51	0.89	.020	.035	5
b2	1,14	1.78	.045	.070	
b3	1,14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1,14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270		4
Ε	9,65	10.67	.380	.420	3,4
ΕÍ	6.22	-	.245		4
e	2.54	BSC	.100	BSC	
Н	14,61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	-	1.65	-	.066	4
L2	1.27	1.78	-	.070	
L3	0.25	0.25 BSC		BSC	
L4	4.78	5.28	.188	.208	

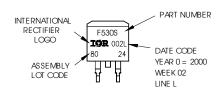
LEAD ASSIGNMENTS HEXFEI 1.- CATE 2. 4.- DRAIN 3.- SOURCE IGBTs, CoPACK 1.- CATE 2. 4.- COLLECTOR 3.- EMITTER DIODES 1.- ANODE * 2. 4.- CATHODE 3.- ANODE * 4.- CATHODE * 4.- CA

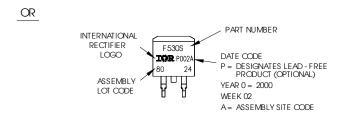
* PART DEPENDENT.

D²Pak (TO-263AB) Part Marking Information



Note: "P" in assembly line position indicates "Lead — Free"



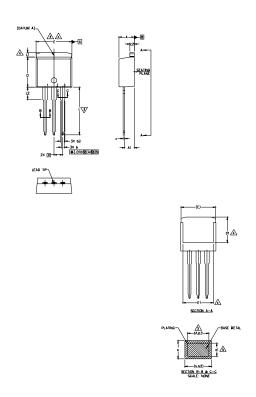


Notes:

- 1. For an Automotive Qualified version of this part please see http://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

TO-262 Package Outline

Dimensions are shown in millimeters (inches)



- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3\DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- 4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
- 6. CONTROLLING DIMENSION: INCH.
- 7.— OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(mox.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

S M B O L	DIMENSIONS					
B	MILLIM	ETERS	INC	ZOTES		
L	MIN.	MAX.	MIN.	MAX.	5	
Α	4.06	4.83	.160	.190		
A1	2.03	3.02	.080	.119		
ь	0.51	0.99	.020	.039		
ь1	0.51	0.89	.020	.035	5	
b2	1.14	1.78	.045	.070		
b3	1.14	1.73	.045	.068	5	
С	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1,14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	-	.270	-	4	
Ε	9,65	10,67	.380	.420	3,4	
E1	6,22	-	.245		4	
e	2,54	BSC	.100	BSC		
L	13,46	14,10	.530	.555		
L1	-	1.65	-	.065	4	
L2	3.56	3.71	.140	.146		

LEAD ASSIGNMENTS

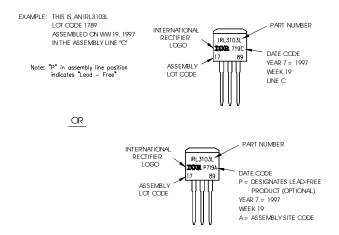
<u>HEXFET</u>

- 1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

IGBTs, CoPACK

- 1.- GATE
 2.- COLLECTOR
 3.- EMITTER
 4.- COLLECTOR

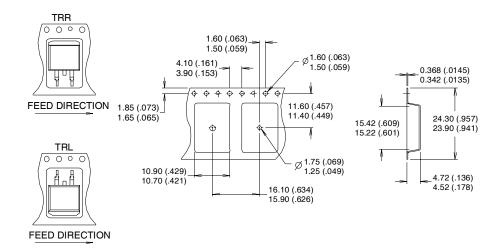
TO-262 Part Marking Information

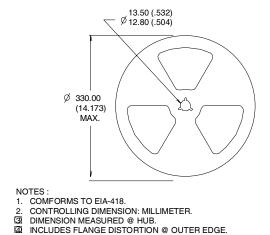


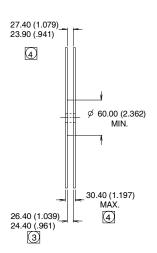
- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

D²Pak Tape & Reel Information

Dimensions are shown in millimeters (inches)







TO-220AB package is not recommended for Surface Mount Application.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.

International

Rectifier

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

TAC Fax: (310) 252-7903

Visit us at www.irf.com for sales contact information. 09/2010

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